

Notice of References Cited	Application/Control No. 10/562,408		Applicant(s)/Patent Under Reexamination YOU ET AL.	
	Examiner Anne Marie S. Wehbe		Art Unit 1633	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,468,793	10-2002	Teem, John L.	435/325
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*	N	WO 01/32898	05-2001	WO	Yonemitsu et al.	
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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